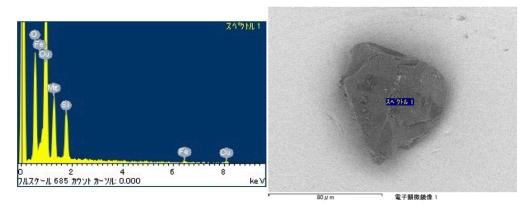
Sample handling

Samples returned from Initial analysis

Samples were picked up one by one in a clean chamber filled with purified N2 with an electrostatic micromanipulator system from a quartz disk, on which they had been fallen from a sample catcher of the Hayabusa spacecraft to be recovered. Then they were set to a sample holder made of cupper and analyzed with an secondary electron microscope equipped with electron dispersive X-ray spectrometer (SEM-EDS) for their initial characterization based on their SEM images and EDS spectra. Therefore, their EDS spectra in the sample catalog show artifact cupper peaks coming from their backgrounds (Figure).



The current condition of the sample is summarized in the sample catalog list, and its recent pictures are also shown in each sample PDF file. You can also check possible damages to the samples given by principal investigators of the initial analysis in "Sample Results Summary Sheet" in the PDFs.

New samples for the AO

Samples were picked up as same as those for the initial analyses, and set to a sample holder made of gold and analyzed with SEM-EDS, so that their EDS spectra in the sample catalog show artifact gold peaks coming from their backgrounds (Figure)

